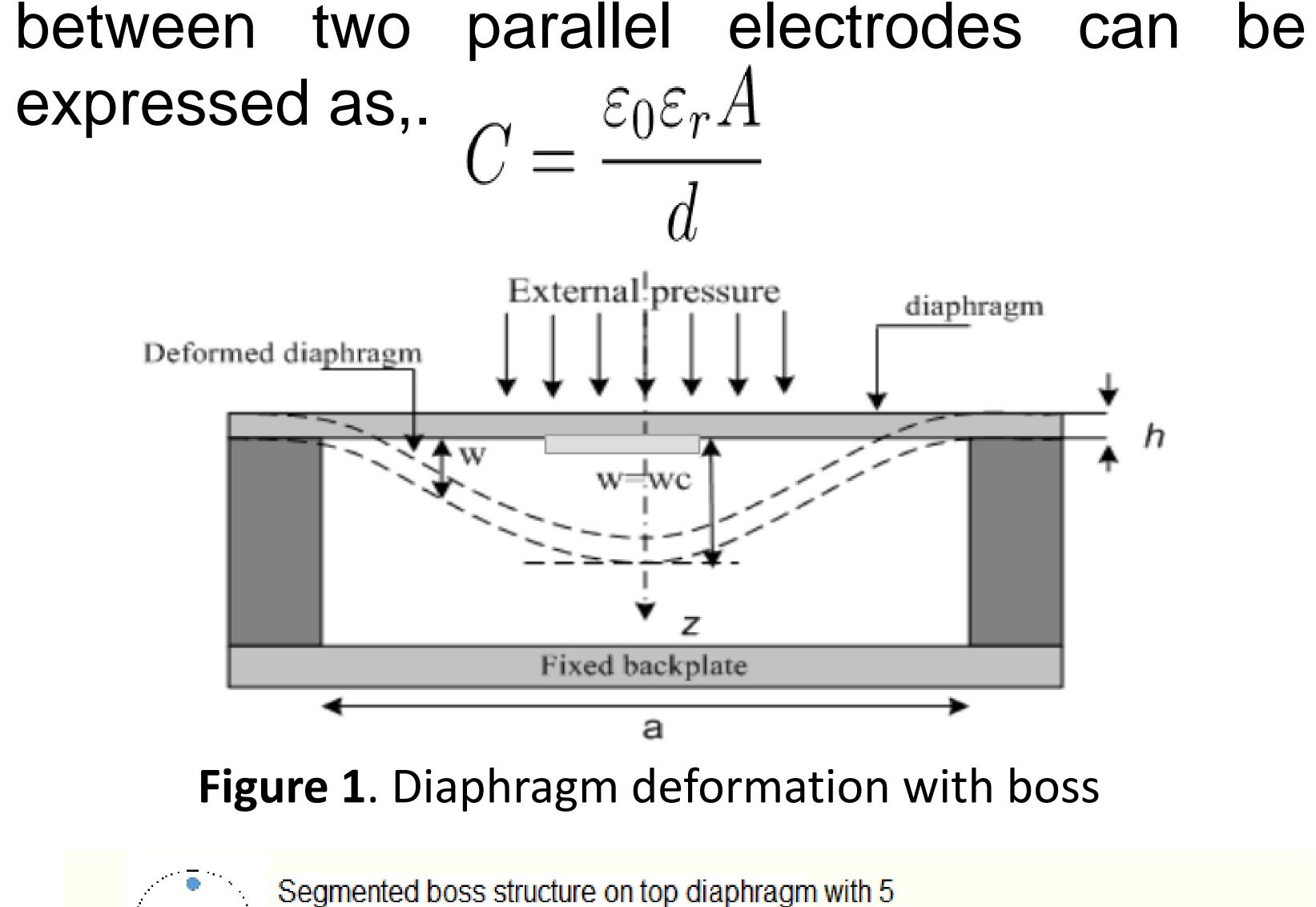
## FEM Analysis Of MEMS Capacitive Pressure Sensor with Segmented Boss Structure For Diaphragm A. K. Ramesh<sup>1</sup>, P. Ramesh<sup>1</sup>

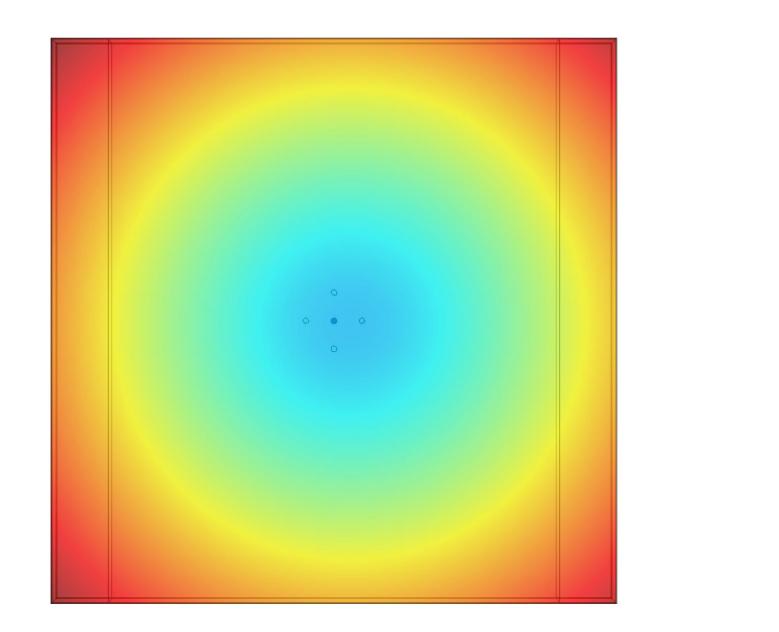
1. College of Engineering Munnar, Munnar, Kerala, India

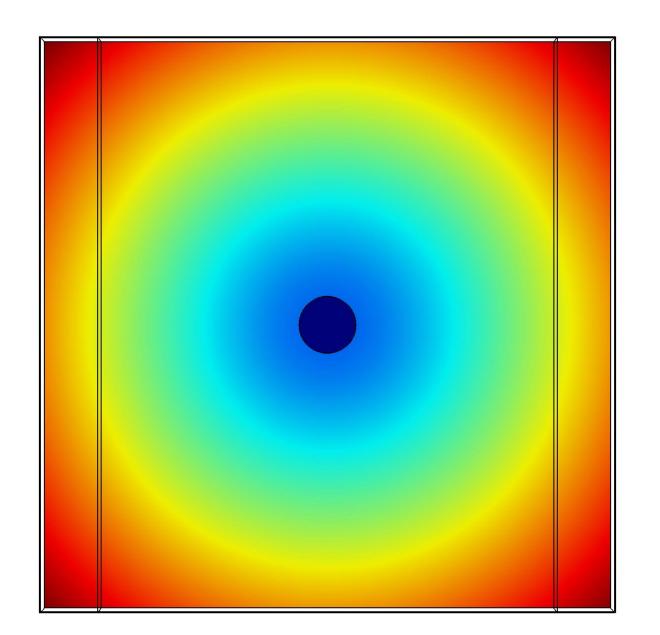
Introduction: MCPS is of great concern when meterology is scaling down to micrometers, The deflection in the diaphragm due to change in pressure produces a change in capacitance. The capacitance

**Results**: Figure 3 and 4 shows the FEM results of diaphragm with segmented boss structure and boss structure for the MEMS CPS diaphragm respectively. The graph plots diaphragm displacement against applied pressure.

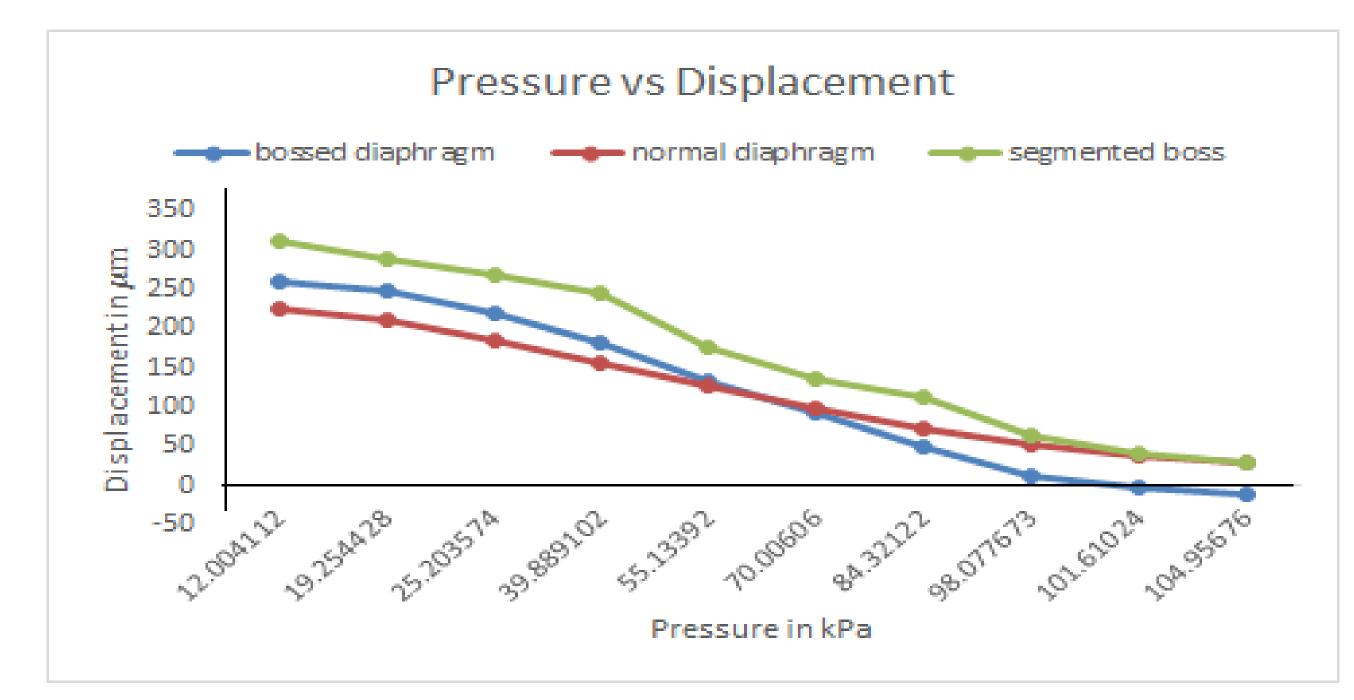


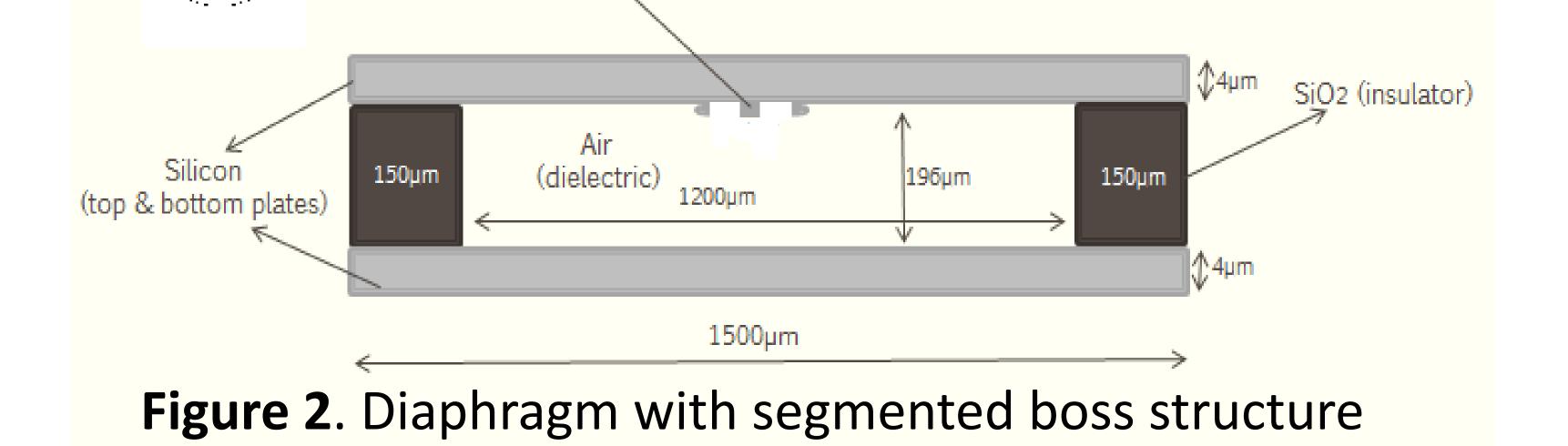
segments (segments highlited in the circle)





## Figure 3. Title of the figure Figure 4. Title of the figure





## **Computational Method:** .

The above equations describes the MCPS segfunctioning physically, but for Finite element be Analysis (FEA) the computation will be based segon certain conditions that define the problem **Re** and it will be based on the equation. 1.

Figure 5. Graph showing the sensitivity and range

Conclusion: The FEM analysis found that the backpressure was reduced after segmentation of boss structure which can be used in applications with improved sensitivity and uncompromised range. References:

1. Akhil K. Ramesh, Ramesh P., "Trade-off between sensitivity and dynamic range in

$$\frac{\partial^4 w(x,y)}{\partial^4 x} + 2 \frac{\partial^4 w(x,y)}{\partial^2 x \partial^2 y} + \frac{\partial^4 w}{\partial^4 x} = \frac{P(x,y)}{D}$$

Where P(x,y) is the applied pressure and

$$D = \frac{Eh^3}{12(1-\nu^2)}$$

So the deflection w(x,y) is calculated by solving this PDE in all the nodes of the mesh.

designing MEMS capacitive pressure sensor," in TENCON 2015 IEEE Region 10 Conference, pp. 1–3, IEEE, 2015
P. Eswaran, S. Malarvizhi, "Sensitivity analysis on mems capacitive differential pressure sensor with bossed diaphragm membrane," in Devices, Circuits and Systems (ICDCS), 2012 International Conference on, pp. 704–707, IEEE, 2012

Excerpt from the Proceedings of the 2016 COMSOL Conference in Bangalore